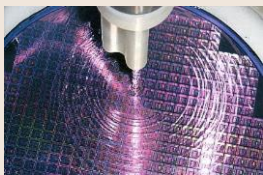


XPER IP Mini

Powerful and affordable non-destructive
thickness measuring system
by NANOBASE



For what applications do we need **Xper-IP Mini**?



Semiconductor

- Wafer
- Si for PV panel



Flat Panel Display

- TFT-LCD, AM-OLED
- Diamond-like carbon
- High-functional film



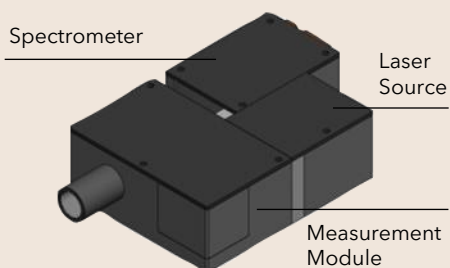
Films and Polymers

- Optical film
- Medical polymer materials

Why do our customers choose **Xper-IP Mini**?

- Absolute thickness measurement with accuracy of $\pm 0.2\%$ in full range
- Exceptional long-term measurement repeatability of $\pm 0.003\%$ in full range
- Broad measurement range of 1.2 mm to 0.03 mm
- Intuitive software with both-surface analysis capacity
- Simultaneous multiple layer measuring capability
- Rugged and compact design suitable for laboratory and manufacturing environments

Xper-IP Mini Specifications



Product Size

144.5 x 90 x 37 (mm)

Thickness Measurement Sensor Head

- Resolution (Z): 10 nm
- Accuracy (Z): $\pm 0.2\%$ of full scale
- Standoff distance: up to 150 mm from objective
- Measurement range (Z): 0.03 ~ 1.2 mm
- Measurement speed: 100 Hz

Laser Source

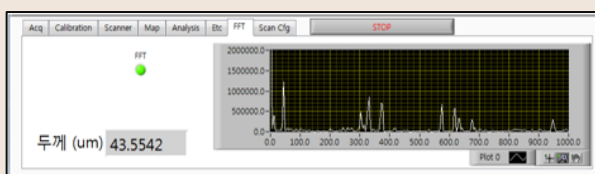
840 nm SLD

Surface Profile Measurement Sensor Head Options

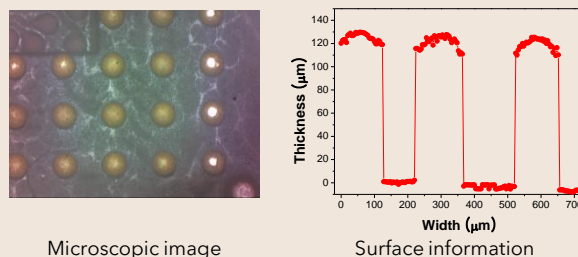
- One shot measurement range (X): 0.5 ~ 2 mm
- One shot measurement data count: 100 points
- Resolution (X): 5 ~ 20 μm depending on an objective lens
- Resolution (Z): 15 nm
- Accuracy (Z): $\pm 0.2\%$ of full scale
- Measurement range (Z): 1.8 mm
- Measurement speed: 30 Hz

Xper-IP Mini Measurement Data

Interferometric Thickness Measurement



Interferometric Surface Measurement



Microscopic image

Surface information